

Fuel Cell MEA Manufacturing R&D

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Project ID #
MF2

This presentation does not contain any proprietary, confidential, or otherwise restricted information

Timeline

- Start: July, 2007
- End: December, 2009
- 25% complete

Budget

- Total project funding
 - \$2,585,000 (AOP project)
- Funding received in FY07
 - \$414,242
- Funding for FY08
 - \$485,000 operating
 - \$250,000 capital

Barriers

Barrier	Target
B: Cost (fuel cell)	\$45/kW (2010) at 500,000 stacks/yr
F: Low levels of quality control (manufacturing)	50x stack cost reduction

Partners

- NREL – Lead
- LBNL – Modeling
- DJW Technology – Consulting
- **DuPont, BASF, Arkema, 3M – Guidance, Test Materials**
- Colorado School of Mines – Fuel cell testing
- University of Hawaii – Segmented cell development

Objectives

- **Background:**
 - Fuel cell system cost targets are based on a **projection of 500,000 units/year**
 - The supplier base needs high speed manufacturing methods – and quality control methods to support them – to achieve these volumes
- **Project objectives:**
 - Evaluate and develop in-line diagnostics for MEA component quality control, and validate in-line
 - Investigate the effects of manufacturing defects on MEA performance and durability
 - Further develop and validate models to predict the effects of local variations in MEA component properties

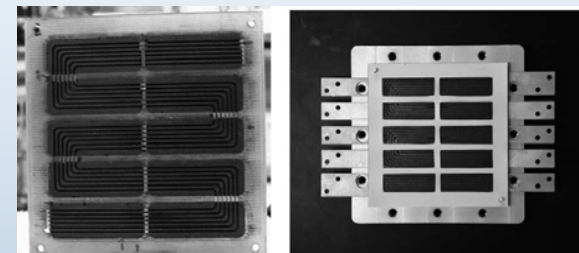
Milestones

Month/year	Deliverable
9/07	Initial report on thickness measurement for MEA components
9/08	Interim database of performance and durability data, and model
9/08	Demonstrate prototype diagnostics
9/08	Go/No-go decision on segmented cell development
12/09	Validated diagnostics with database
12/09	Refined model
9/11	<i>MYPP: Develop prototype sensors for quality control of MEA manufacturing</i>
9/12	<i>MYPP: Develop continuous in-line measurement of MEA fabrication</i>
9/13	<i>MYPP: Demonstrate sensors in pilot-scale applications for manufacturing MEAs</i>
9/13	<i>MYPP: Establish models to predict the effect of manufacturing variations on MEA performance</i>

Approach



- **Diagnostic development:**
 - Evaluate commercially available in-line diagnostics as a baseline
 - Focus initially on thickness as a “proto-measurement” for continuous processing
 - Identify (industry input) and address critical parameters for each component
 - **Utilize NREL diagnostic-development capabilities relative to photovoltaics manufacturing**
 - Refine techniques and systems based on understanding of critical defect size
 - **Validate systems using research web-line**
- **Fuel cell testing:**
 - Use standard performance tests and accelerated aging
 - **Develop project-specific testing capabilities**
 - Segmented cell development at HNEI
 - **Investigate critical defect size**
 - “Design” MEAs with defects to study effects
 - **Input to diagnostics system requirements (resolution/accuracy)**
- **Modeling:**
 - Use and refine existing LBNL pseudo 2-D performance model and development roadmap
 - Validate model with experimental results
 - **Refine and simplify model based on industry input and results**
 - **Assist in creation of transfer functions**
 - Incorporate transient (degradation) phenomena as necessary to model durability



G. Bender et al. / Journal of Power Sources 123 (2003) 163–171

- **Strong support from industry**
 - Non-disclosure agreements in place
 - Identified MEA component critical parameters
 - e.g., Pt content & distribution, electrode and GDL porosity, caliper, GDL and microlayer surface structure, hydrophobicity and conductivity of GDL, extent of ionomer cure
 - Defining and making MEA samples with component defects
- **Outfitting manufacturing R&D labs**
- **Initiated collaboration with University of Hawaii for segmented cell development**
- **Initial model development and roadmap complete**
- **Working to specify web-line**

Technical Accomplishments

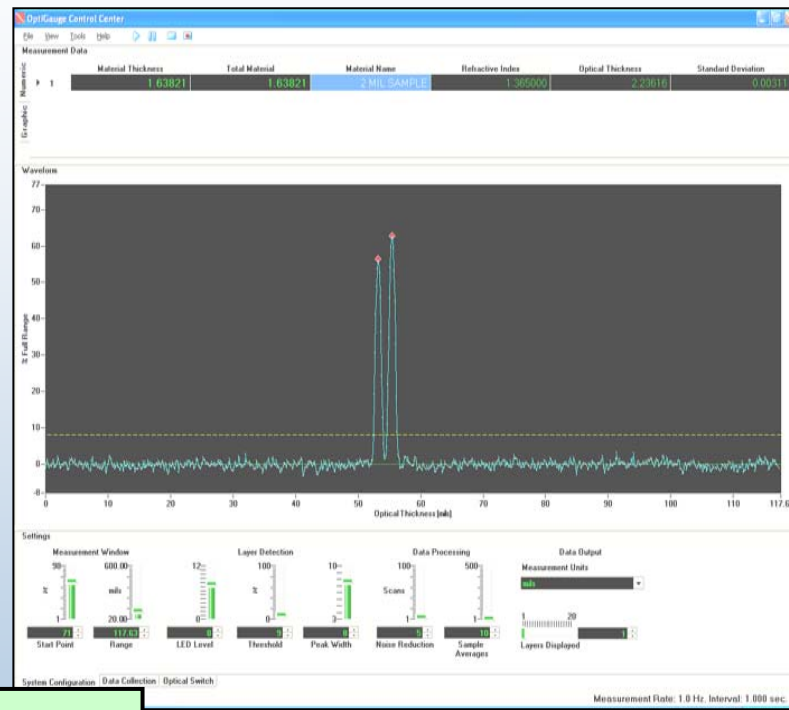
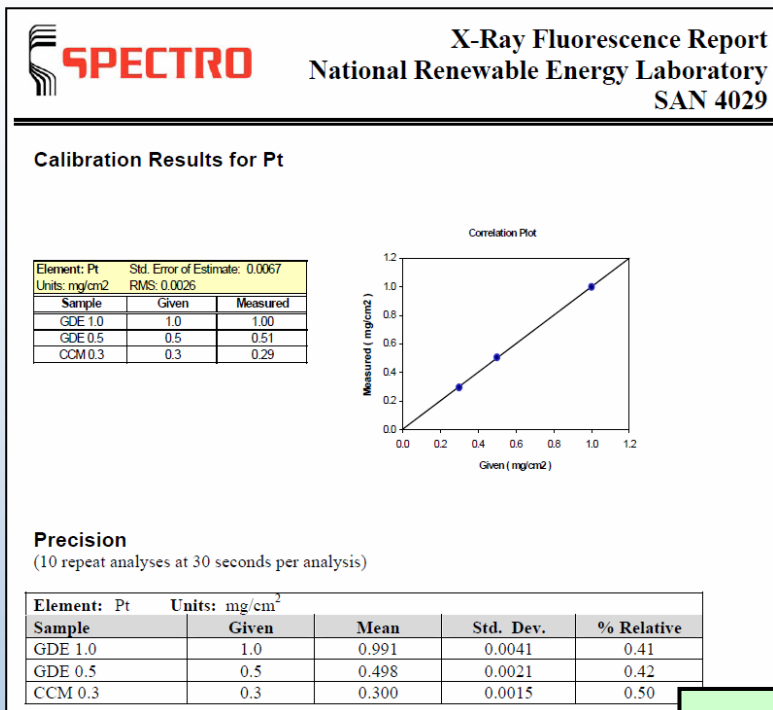
- Submitted report, “Preliminary assessment of measurement techniques,” in September
 - Reported on techniques relevant to in-line thickness measurement of MEA components
 - Suppliers evaluated small samples (not in-line) of commercially available MEA components
 - Also included developmental systems at NREL and LBNL
 - ***Input from industry partners: Limitations of most commercial systems lead to either averaging over large areas or measuring at only one location***
 - ***Spot (measurement) size***
 - ***Data acquisition speed***
 - ***Techniques often not optimized for specific materials***
 - ***Resolution, repeatability***

Technical Accomplishments

Technique	Vendor	Status	Applicability
Optical/IR Reflection	Lumetrics, Infocus	Complete	Membrane
Laser Triangulation	Infocus	Complete	GDE, GDL, possibly CCM
Low-force Contact	Infocus	Complete	All, but in-line implementation may be difficult
Beta- / Gamma- / X-ray	Thermo Fisher, NDC, Mahlo	Need larger samples	Possibly all
X-ray Fluorescence	Fischer, Spectro	Complete	Catalyst, possibly membrane
Capacitance	Infocus	Complete	Questionable, but could measure conductance

Techniques applicable to MEA components

Technical Accomplishments



MEA components can be measured on the bench-top

XRF:

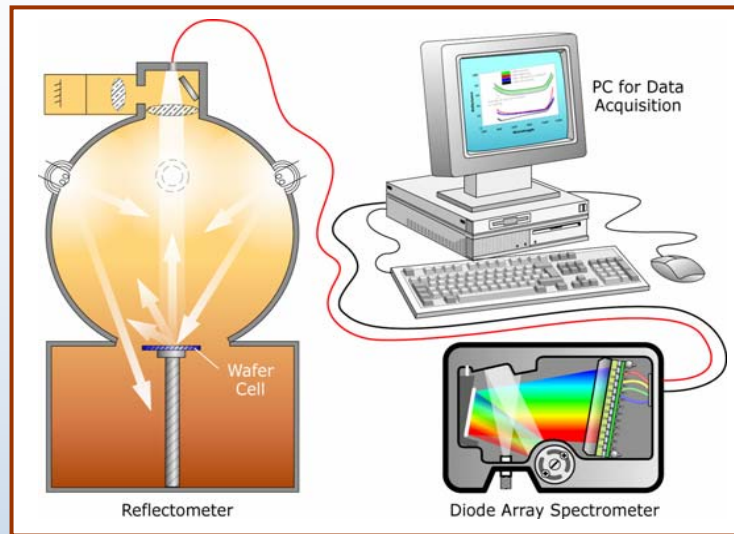
- Fischer Technology and Spectro
- Coatings with 0.3, 0.5, and 1.0 mg/cm² Pt

Optical:

- Lumetrics and Infocus
- 1, 2 and 5 mil Nafion membranes

Technical Accomplishments

- **Completed initial assessment of NREL-developed Optical Reflectometer**
 - Used in PV continuous manufacturing
 - Data acquisition and signal processing exists
 - Optical characterization of all MEA components
 - Potential for measurement of thickness, composition, porosity, surface structure, conductivity...
 - Demonstrated simultaneous measurements indicative of membrane thickness and composition



Technology has potential to address:

- Multiple critical parameters
- Multiple MEA component materials
- Rapid, large area measurement

Technical Accomplishments

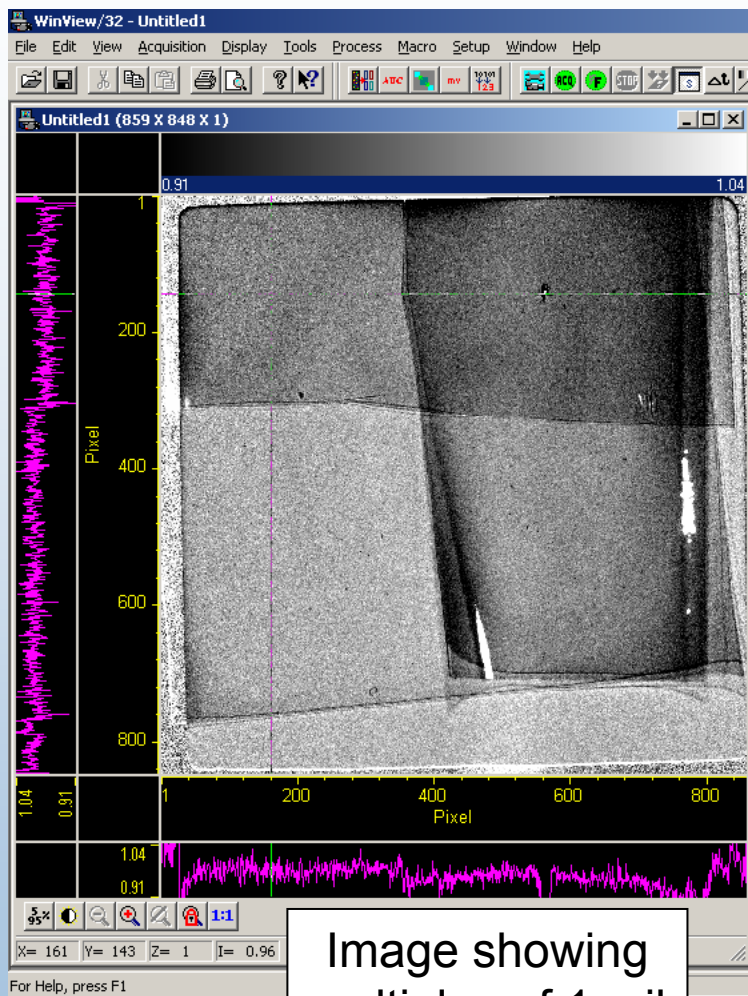
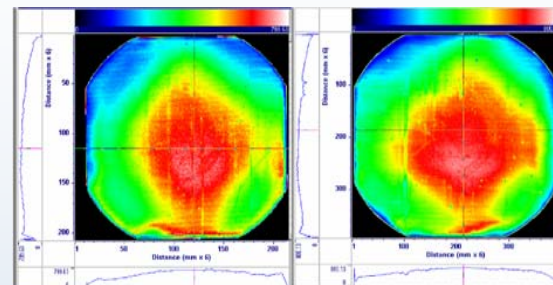


Image showing multiples of 1 mil membrane thickness



~ 25 sq-in area single measurement of silicon wafer anti-reflective coating

- **Proof of concept for 2D membrane thickness imaging**
 - Wide angle illumination; normal reflection
 - In continuous processing, area measurement (vs. point measurement) enables identification of discrete defects in addition to point-to-point variation

Future Work

FY08:

- Continue evaluation of optical reflectometer
 - Membrane thickness imaging
 - Improved signal
 - Other materials and parameters
- Initiate single cell testing (NREL, CSM)
- Begin transfer of data and model validation (LBNL)
- Complete segmented cell feasibility study (HNEI)
- Order research web-line

FY09:

- Install web-line
- Modify optical reflectometer and validate in-line
 - Optics and sensors for other materials and parameters
 - Configuration for web measurement
- Assess other diagnostic technologies for development
- Evaluate commercial diagnostics, e.g., XRF, in-line
- Develop segmented cell hardware and methods (HNEI, NREL)
- Investigate critical defect size (NREL, CSM, HNEI)
- Refine and simplify model (LBNL)

Continue to get input on priorities and directions from industry partners

Summary

Objectives: Strong industry buy-in

Approach:

- **Develop in-line quality control diagnostics**
- **Study critical defect size**
- **Develop model and transfer functions for effects of defects**

Progress:

- **Established collaborations with industry and academia**
- **Completed initial report on thickness measurement techniques**
- **Establishing protocols and methodologies for manufacturing R&D**
- **Ongoing evaluation of NREL optical reflectometer**
- **Initial model development and roadmap complete**

Future Work:

- **Evaluation and development of diagnostics for a range of MEA component critical parameters**
- **In-line validation of diagnostics with partners**
- **Segmented cell and other test capabilities specific to evaluation of defects**
- **Model validation and refinement**